## LMX2353

## PLLatinum ${ }^{\text {TM }}$ Fractional N Single 2.5 GHz Low Power Frequency Synthesizer

## General Description

The LMX2353 is a monolithic integrated fractional N frequency synthesizer, designed to be used in a local oscillator subsystem for a radio transceiver. It is fabricated using National's $0.5 \mu \mathrm{ABiC}$ V silicon BiCMOS process. The LMX2353 contains dual modulus prescalers along with modulo 15 or 16 fractional compensation circuitry in the N divider. A 16/17 or $32 / 33$ prescale ratio can be selected for the LMX2353. Using a fractional N phase locked loop technique, the LMX2353 can generate very stable low noise control signals for UHF and VHF voltage controlled oscillators (VCOs).
The LMX2353 has a highly flexible 16 level programmable charge pump which supplies output current magnitudes from $100 \mu \mathrm{~A}$ to 1.6 mA . Two uncommitted CMOS outputs can be used to provide external control signals, or configured to FastLock ${ }^{\top \mathrm{M}}$ mode. Serial data is transferred into the LMX2353 via a three wire interface (Data, LE, Clock). Supply voltage can range from 2.7 V to 5.5 V . The LMX2353 features very low current consumption; typically 5.5 mA at 3.0 V . The LMX2353 is available in a 16-pin TSSOP or a 16-pin CSP surface mount plastic package.

Functional Block Diagram


[^0]Connection Diagrams


TOP VIEW
Order Number LMX2353TM or LMX2353TMX
See NS Package Number MTC16


TOP VIEW
Order Number LMX2353SLBX See NS Package Number SLB16A

## Pin Description

| Pin No. |  | Pin Name | I/O | Description |
| :---: | :---: | :---: | :---: | :---: |
| CSP | TSSOP |  |  |  |
| 16 | 1 | $V_{P}$ | - | Power supply for charge pump. Must be $\geq \mathrm{V}_{\mathrm{CC}}$. |
| 1 | 2 | $\mathrm{CP}_{\circ}$ | O | Charge pump output. Connected to a loop filter for driving the control input of an external VCO. |
| 2 | 3 | GND | - | Ground for PLL digital circuitry. |
| 3 | 4 | $\mathrm{f}_{\mathrm{IN}}$ | I | RF prescaler input. Small signal input from the VCO. |
| 4 | 5 | $\mathrm{f}_{\text {INB }}$ | I | RF prescaler complimentary input. A bypass capacitor should be placed as close as possible to this pin and be connected directly to the ground plane. |
| 5 | 6 | GND | - | Ground for PLL analog circuitry. |
| 6 | 7 | $\mathrm{OSC}_{\text {IN }}$ | I | Oscillator input. A CMOS inverting gate input. The input has a $\mathrm{V}_{\mathrm{CC}} / 2$ input threshold and can be driven from an external CMOS or TTL logic gate. |
| 7 | 8 | FoLD | O | Multiplexed output of N or R divider and lock detect. CMOS output. |
| 8 | 9 | CE | I | PLL Enable. Powers down N and R counters, prescalers, and TRI-STATE ${ }^{\circledR}$ charge pump output when LOW. Bringing CE high powers up PLL depending on the state of CTL_WORD. |
| 9 | 10 | CLK | I | High impedance CMOS Clock input. Data for the various counters is clocked into the 24-bit shift register on the rising edge. |
| 10 | 11 | DATA | I | Binary serial data input. Data entered MSB first. The last two bits are the control bits. High impedance CMOS input. |
| 11 | 12 | LE | I | Load enable high impedance CMOS input. Data stored in the shift registers is loaded into one of the 4 internal latches when LE goes HIGH. |
| 12 | 13 | GND | - | Ground. |
| 13 | 14 | $\mathrm{V}_{\mathrm{Cc}}$ | - | PLL power supply voltage input. May range from 2.7 V to 5.5 V . Bypass capacitors should be placed as close as possible to this pin and be connected directly to the ground plane. |
| 14 | 15 | OUT1 | - | Programmable CMOS output. Level of the output is controlled by F2[18] bit. |
| 15 | 16 | OUTO | - | Programmable CMOS output. Level of the output is controlled by F2[17] bit. |

Absolute Maximum Ratings (Notes 1, 2) If Military/Aerospace specified devices are required, please contact the National Semiconductor Sales Office/ Distributors for availability and specifications.

| Power Supply Voltage |  |
| :--- | ---: |
| $\mathrm{V}_{\mathrm{CC}}$ | -0.3 V to 6.5 V |
| Vp | -0.3 V to 6.5 V |
| Voltage on any pin with |  |
| GND $=0 \mathrm{~V}\left(\mathrm{~V}_{1}\right)$ | -0.3 V to $\mathrm{V}_{\mathrm{CC}}+0.3 \mathrm{~V}$ |
| Storage Temperature Range $\left(\mathrm{T}_{\mathrm{S}}\right)$ | $-65^{\circ} \mathrm{C}$ to $+150^{\circ} \mathrm{C}$ |
| Lead Temperature (solder, 4 sec.$)\left(\mathrm{T}_{\mathrm{L}}\right)$ | $+260^{\circ} \mathrm{C}$ |

## Recommended Operating Conditions

Power Supply Voltage

| $V_{C C}$ | 2.7 V to 5.5 V |
| :--- | ---: |
| Vp | $\mathrm{V}_{\mathrm{CC}}$ to 5.5 V |
| Operating Temperature $\left(\mathrm{T}_{\mathrm{A}}\right)$ | $-40^{\circ} \mathrm{C}$ to $+85^{\circ} \mathrm{C}$ |

Operating Temperature ( $T_{A}$ )
$-40^{\circ} \mathrm{C}$ to $+85^{\circ} \mathrm{C}$
Note 1: Absolute Maximum Ratings indicate limits beyond which damage to the device may occur. Operating Ratings indicate conditions for which the device is intended to be functional, but do not guarantee specific performance limits. For guaranteed specifications and test conditions, see the Electrical Characteristics. The guaranteed specifications apply only for the test conditions listed.

Note 2: This device is a high performance RF integrated circuit with an ESD rating $<2 \mathrm{kV}$ and is ESD sensitive. Handling and assembly of this device should only be done at ESD free workstations.

Electrical Characteristics ( $\mathrm{V}_{\mathrm{CC}}=\mathrm{Vp}=3.0 \mathrm{~V} ;-40^{\circ} \mathrm{C}<\mathrm{T}_{\mathrm{A}}<85^{\circ} \mathrm{C}$ except as specified).
All min/max specifications are guaranteed by design, or test, or statistical methods

| Symbol | Parameter | Conditions | Value |  |  | Unit |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: |
|  |  |  | Min | Typ | Max |  |
| GENERAL |  |  |  |  |  |  |
| $\mathrm{I}_{\mathrm{Cc}}$ | Power Supply Current |  |  | 5.5 | 6.75 | mA |
| $\mathrm{I}_{\text {CC-PWDN }}$ | Power Down Current | CE = LOW |  | 5 | 20 | $\mu \mathrm{A}$ |
| $\mathrm{f}_{\mathrm{IN}}$ | RF Operating Frequency | (Note 3) | 0.5 |  | 2.5 | GHz |
| $\mathrm{f}_{\text {OSC }}$ | Oscillator Frequency | (Note 3) | 2 |  | 50 | MHz |
| f $\phi$ | Phase Detector Frequency |  |  |  | 10 | MHz |
| $\mathrm{Pf}_{\mathrm{IN}}$ | RF Input Sensitivity | $2.7 \mathrm{~V} \leq \mathrm{V}_{\mathrm{Cc}}<3.0 \mathrm{~V}$ | -15 |  | 0 | dBm |
|  |  | $3.0 \mathrm{~V} \leq \mathrm{V}_{\mathrm{CC}} \leq 5.0 \mathrm{~V}$ | -10 |  | 0 | dBm |
| $\mathrm{V}_{\text {OSC }}$ | Oscillator Sensitivity | $\mathrm{OSC}_{\text {IN }}$ | 0.5 |  | $\mathrm{V}_{\mathrm{Cc}}$ | $\mathrm{V}_{\mathrm{PP}}$ |
| CHARGE PUMP |  |  |  |  |  |  |
| ICP ${ }_{\text {o-source }}$ | Charge Pump Output Current | $\begin{aligned} & \mathrm{VCP}_{\circ}=\mathrm{Vp} / 2, \\ & \mathrm{CP} \text { _WORD }=0000 \end{aligned}$ |  | -100 |  | $\mu \mathrm{A}$ |
| ICP ${ }_{\text {o-sink }}$ |  | $\begin{aligned} & \mathrm{VCP}{ }_{\circ}=\mathrm{Vp} / 2, \\ & \mathrm{CP} \text { _WORD }=0000 \end{aligned}$ |  | 100 |  | $\mu \mathrm{A}$ |
| $\mathrm{ICP}_{\text {o-source }}$ |  | $\begin{aligned} & \mathrm{VCP}_{\mathrm{o}}=\mathrm{Vp} / 2, \\ & C P_{-} \mathrm{WORD}=1111 \end{aligned}$ |  | -1.6 |  | mA |
| ICP ${ }_{\text {o-sink }}$ |  | $\begin{aligned} & \mathrm{VCP}_{\mathrm{o}}=\mathrm{Vp} / 2, \\ & \mathrm{CP} \text { _WORD }=1111 \end{aligned}$ |  | 1.6 |  | mA |
| $\mathrm{ICP}_{\text {o-TRI }}$ | Charge Pump TRI-STATE Current | $\begin{aligned} & 0.5 \leq V C P_{o} \leq V p-0.5, \\ & -40^{\circ} \mathrm{C}<\mathrm{T}_{\mathrm{A}}<85^{\circ} \mathrm{C} \\ & \hline \end{aligned}$ | -2.5 |  | 2.5 | nA |
| $\begin{aligned} & \text { ICP }{ }_{\mathrm{o} \text {-sink }} \mathrm{vs} \\ & \mathrm{ICP} \\ & \hline \text { o-source } \\ & \hline \end{aligned}$ | CP Sink vs Source Mismatch | $\mathrm{VCP}_{\mathrm{o}}=\mathrm{Vp} / 2, \mathrm{~T}_{\mathrm{A}}=25^{\circ} \mathrm{C}$ |  | 3 | 10 | \% |
| $\begin{aligned} & \text { ICPo vs } \\ & \text { VCP。 } \end{aligned}$ | CP Current vs Voltage | $0.5 \leq \mathrm{VCP}_{\mathrm{o}} \leq \mathrm{Vp}-0.5, \mathrm{~T}_{\mathrm{A}}=25^{\circ} \mathrm{C}$ |  | 4 | 15 | \% |
| $\mathrm{ICP}_{\text {o }}$ vs T | CP Current vs Temperature | $\mathrm{VCP}_{\mathrm{o}}=\mathrm{Vp} / 2,-40^{\circ} \mathrm{C}<\mathrm{T}_{\mathrm{A}}<85^{\circ} \mathrm{C}$ |  | 8 |  | \% |
| DIGITAL INTERFACE (DATA, CLK, LE, CE, FoLD) |  |  |  |  |  |  |
| $\mathrm{V}_{\mathrm{IH}}$ | High-Level Input Voltage | (Note 4) | $0.8 \mathrm{~V}_{\mathrm{CC}}$ |  |  | V |
| $\mathrm{V}_{\text {IL }}$ | Low-Level Input Voltage | (Note 4) |  |  | $0.2 \mathrm{~V}_{\mathrm{CC}}$ | V |
| ${ }^{1}$ | High-Level Input Current | $\mathrm{V}_{\mathrm{IH}}=\mathrm{V}_{\mathrm{CC}}=5.5 \mathrm{~V}$, (Note 4) | -1.0 |  | 1.0 | $\mu \mathrm{A}$ |
| ${ }_{\text {IL }}$ | Low-Level Input Current | $\mathrm{V}_{\mathrm{IL}}=0, \mathrm{~V}_{\mathrm{CC}}=5.5 \mathrm{~V}$, (Note 4) | -1.0 |  | 1.0 | $\mu \mathrm{A}$ |
| ${ }^{\text {IH }}$ | Oscillator Input Current | $\mathrm{V}_{\mathrm{IH}}=\mathrm{V}_{\mathrm{CC}}=5.5 \mathrm{~V}$ |  |  | 100 | $\mu \mathrm{A}$ |
| IL | Oscillator Input Current | $\mathrm{V}_{\mathrm{IL}}=0, \mathrm{~V}_{\mathrm{CC}}=5.5 \mathrm{~V}$ | -100 |  |  | $\mu \mathrm{A}$ |
| $\mathrm{V}_{\mathrm{OH}}$ | High-Level Output Voltage | $\mathrm{I}_{\mathrm{OH}}=-500 \mu \mathrm{~A}$ | $\begin{gathered} \hline \mathrm{V}_{\mathrm{CC}}- \\ 0.4 \end{gathered}$ |  |  | V |
| $\mathrm{V}_{\mathrm{OL}}$ | Low-Level Output Voltage | $\mathrm{I}_{\mathrm{OL}}=500 \mu \mathrm{~A}$ |  |  | 0.4 | V |

Electrical Characteristics $\left(\mathrm{V}_{\mathrm{CC}}=\mathrm{Vp}=3.0 \mathrm{~V} ;-40^{\circ} \mathrm{C}<\mathrm{T}_{\mathrm{A}}<85^{\circ} \mathrm{C}\right.$ except as specified).
All min/max specifications are guaranteed by design, or test, or statistical methods (Continued)

| Symbol | Parameter | Conditions | Value |  |  | Unit |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: |
|  |  |  | Min | Typ | Max |  |
| MICROWIRE TIMING |  |  |  |  |  |  |
| $\mathrm{t}_{\mathrm{CS}}$ | Data to Clock Setup Time | See Data Input Timing | 50 |  |  | ns |
| $\mathrm{t}_{\mathrm{CH}}$ | Data to Clock Hold Time | See Data Input Timing | 10 |  |  | ns |
| $\mathrm{t}_{\text {CWH }}$ | Clock Pulse Width High | See Data Input Timing | 50 |  |  | ns |
| $\mathrm{t}_{\text {cWL }}$ | Clock Pulse Width Low | See Data Input Timing | 50 |  |  | ns |
| $\mathrm{t}_{\text {ES }}$ | Clock to Load Enable Setup Time | See Data Input Timing | 50 |  |  | ns |
| $\mathrm{t}_{\text {EW }}$ | Load Enable Pulse Width | See Data Input Timing | 50 |  |  | ns |

Note 3: Minimum operating frequencies are not production tested - only characterized.
Note 4: Except $f_{I N}$ and $O S C_{I N}$.

## Charge Pump Current Specification Definitions



I1 $=\mathrm{CP}$ sink current at $\mathrm{V}_{\mathrm{CPo}}=\mathrm{V}_{\mathrm{P}}-\Delta \mathrm{V}$
$\mathrm{I} 2=\mathrm{CP}$ sink current at $\mathrm{V}_{\mathrm{CPo}}=\mathrm{V}_{\mathrm{p} / 2}$
$\mathrm{I} 3=\mathrm{CP}$ sink current at $\mathrm{V}_{\mathrm{CPo}}=\Delta \mathrm{V}$
$14=\mathrm{CP}$ source current at $\mathrm{V}_{\mathrm{CPo}}=\mathrm{V}_{\mathrm{P}}-\Delta \mathrm{V}$
$15=\mathrm{CP}$ source current at $\mathrm{V}_{\mathrm{CPo}}=\mathrm{V}_{\mathrm{p}} / 2$
$\mathrm{I} 6=\mathrm{CP}$ source current at $\mathrm{V}_{\mathrm{CPo}}=\Delta \mathrm{V}$
$\Delta \mathrm{V}=$ Voltage offset from positive and negative rails. Dependent on VCO tuning range relative to $\mathrm{V}_{\mathrm{CC}}$ and ground. Typical values are between 0.5 V and 1.0 V .
Note 5: $\mathrm{I}_{\mathrm{CPo}}$ vs $\mathrm{V}_{\mathrm{CPo}}=$ Charge Pump Output Current magnitude vs Variation Voltage $=$ $[1 / 2$ * $\{|11|-||3|\}] /[1 / 2 *\{|11|+||3|\}] * 100 \%$ and $[1 / 2 *\{|14|-|16|\}] /[1 / 2 *\{|14|+||6|\}] * 100 \%$
Note 6: $\mathrm{I}_{\mathrm{CPo} \text {-SINK vs }} \mathrm{I}_{\mathrm{CPo} \text {-SOURCE }}=$ Charge Pump Output Current Sink vs Source Mismatch $=$ [||2| - ||5|]/ [1/2 * \{||2| + |15|\}] * $100 \%$
Note 7: $\mathrm{I}_{\mathrm{CPo}} \mathrm{vs} \mathrm{T}_{\mathrm{A}}=$ Charge Pump Outpuit Current magnitude variation vs Temperature = $\left[\left|\mid 2 @\right.\right.$ templ-||2@ $\left.\left.25^{\circ} \mathrm{C}\right|\right] /\left|\left|2 @ 25^{\circ} \mathrm{C}\right| * 100 \%\right.$ and $| \mid 5$ @temp|-||5@ $25^{\circ} \mathrm{C}\left|/\left|\left|5 @ 25^{\circ} \mathrm{C}\right| * 100 \%\right.\right.$

Typical Performance Characteristics


DS101124-10

Charge Pump Current vs $\mathrm{CP}_{\text {o }}$ Voltage CP_WORD = 0011 and 1111

$I_{\text {CPO }}$ TRI-STATE vs CP ${ }_{\text {o }}$ Voltage


Sink vs Source Mismatch
(See (Note 6) under Charge Pump Current Specification Definitions)


LMX2353 $\mathrm{V}_{\mathrm{P}}$ Voltage vs $\mathrm{V}_{\mathrm{P}}$ Load Current in V Doubler Mode, $\mathrm{T}=\mathbf{2 5}{ }^{\circ} \mathrm{C}$


## Typical Performance Characteristics (Continued)

## LMX2353 Sensitivity vs Frequency



Oscillator Input Sensitivity vs Frequency


## RF Input Impedence

$\mathrm{Vcc}=2.7 \mathrm{~V}$ to $5.5 \mathrm{~V}, \mathrm{f}_{\mathrm{IN}}=50 \mathrm{MHz}$ to
$3 \mathrm{GHz}\left(\mathrm{f}_{\mathrm{INB}}\right.$ Capacitor $=\mathbf{1 0 0} \mathrm{pF}$ )


Marker $1=1 \mathrm{GHz}$, Real $=130$, Imaginary $=-153$
Marker $2=2 \mathrm{GHz}$, Real $=44$, $\operatorname{Imaginary~}=-73$
Marker $3=3 \mathrm{GHz}$, Real $=25$, Imaginary $=-32$
Marker $4=500 \mathrm{MHz}$, Real $=246$, Imaginary $=-203$
S101124-14

### 1.0 Functional Description

The basic phase-lock-loop (PLL) configuration consists of a high-stability crystal reference oscillator, a frequency synthesizer such as the National Semiconductor LMX2353, a voltage controlled oscillator (VCO), and a passive loop filter. The frequency synthesizer includes a phase detector, current mode charge pump, as well as programmable reference [R] and feedback [N] frequency dividers. The VCO frequency is established by dividing the crystal reference signal down via the R counter to obtain a frequency that sets the comparison frequency. This reference signal, fr, is then presented to the input of a phase/frequency detector and compared with another signal, fp , the feedback signal, which was obtained by dividing the VCO frequency down by way of the N counter and fractional circuitry. The phase/frequency detector's current source outputs pump charge into the loop filter, which then converts the charge into the VCO's control voltage. The phase/frequency comparator's function is to adjust the voltage presented to the VCO until the feedback signal's frequency (and phase) match that of the reference signal. When this "phase-locked" condition exists, the RF VCO's frequency will be N+F times that of the comparison frequency, where N is the integer divide ratio and F is the fractional component. The fractional synthesis allows the phase detector frequency to be

### 1.0 Functional Description (Continued)

increased while maintaining the same frequency step size for channel selection. The division value N is thereby reduced giving a lower phase noise referred to the phase detector input, and the comparison frequency is increased allowing faster switching times.

### 1.1 REFERENCE OSCILLATOR INPUT

The reference oscillator frequency for the PLL is provided by an external reference TCXO through the $\mathrm{OSC}_{\text {IN }}$ pin. $\mathrm{OSC}_{\text {IN }}$ block can operate to 50 MHz with a minimum input sensitivity of $0.5 \mathrm{~V}_{\mathrm{pp}}$. The inputs have a $\mathrm{V}_{\mathrm{cc}} / 2$ input threshold and can be driven from an external CMOS or TTL logic gate.

### 1.2 REFERENCE DIVIDER (R-COUNTER)

The R-counter is clocked through the oscillator block. The maximum frequency is 50 MHz . The R-counter is CMOS design and 15 -bit in length with programmable divider ratio from 3 to 32,767 .

### 1.3 FEEDBACK DIVIDER (N-COUNTER)

The $N$ counter is clocked by the small signal $f_{I N}$ input pin. The $N$ counter is 19 bits with 15 bits integer divide and 4 bits fractional. The integer part is configured as a 5 -bit A counter and a 10-bit B counter. The LMX2353 is capable of operating from 500 MHz to 1.2 GHz with the $16 / 17$ prescaler offering a continuous integer divide range from 272 to 16399 , and 1.2 GHz to 2.5 GHz with the $32 / 33$ prescaler offering a continuous integer divide range from 1056 to 32767 . The fractional compensation is programmable in either $1 / 15$ or $1 / 16$ modes.

### 1.3.1 Prescaler

The RF input to the prescaler consist of $f_{I N}$ and $f_{I N B}$; which are complimentary inputs to a differential pair amplifier. The complimentary input is internally coupled to ground with a 100 pF capacitor. This input is typically AC coupled to ground through external capacitors as well. A 16/17 or 32/33 prescaler ratio can be selected.

### 1.3.2 Fractional Compensation

The fractional compensation circuitry in the N divider allows the user to adjust the VCO's tuning resolution in $1 / 16$ or 1/15 increments of the phase detector comparison frequency. A 4-bit register is programmed with the fractions desired numerator, while another bit selects between fractional 15 and 16 modulo base denominator. An integer average is accomplished by using a 4-bit accumulator. A variable phase delay stage compensates for the accumulated integer phase error, minimizing the charge pump duty cycle, and reducing spurious levels. This technique eliminates the need for compensation current injection in to the loop filter. Overflow signals generated by the accumulator are equivalent to 1 full VCO cycle, and result in a pulse swallow.

### 1.4 PHASE/FREQUENCY DETECTOR

The phase/frequency detector is driven from the $N$ and $R$ counter outputs. The maximum frequency at the phase detector input is about 10 MHz for some high frequency VCO due to the minimum continuous divide ratio of the dual modulus prescaler. If the phase detector frequency exceeds 2.37 MHz , there are higher chances of running into illegal divide ratios, because the minimum continuous divide ratio with a $32 / 33$ prescaler is 1056 . The phase detector outputs control the charge pumps. The polarity of the pump-up or pump-down control is programmed using PD_POL depending on whether the VCO characteristics are positive or negative. The phase detector also receives a feedback signal from the charge pump, in order to eliminate dead zone.

### 1.5 CHARGE PUMPS

The phase detector's current source output pumps charge into an external loop filter, which then integrates into the VCO's control voltage. The charge pump steers the charge pump output $\mathrm{CP}_{\mathrm{o}}$ to $\mathrm{V}_{\mathrm{CC}}$ (pump-up) or Ground (pump-down). When locked, $\mathrm{CP}_{\mathrm{o}}$ is primarily in a TRISTATE mode with small corrections. The charge pump output current magnitude can be selected from $100 \mu \mathrm{~A}$ to 1.6 mA by programming the CP_WORD bits.

### 1.6 VOLTAGE DOUBLER

The $\mathrm{V}_{\mathrm{p}}$ pin is normally driven from an external power supply over a range of $\mathrm{V}_{\mathrm{cc}}$ to 5.5 V to provide current for the RF charge pump circuit. An internal voltage doubler circuit connected between the $\mathrm{V}_{\mathrm{Cc}}$ and $\mathrm{V}_{\mathrm{p}}$ supply pins alternately allows $\mathrm{V}_{\mathrm{Cc}}=3 \mathrm{~V}$ $( \pm 10 \%)$ users to run the RF charge pump circuit at close to twice the $\mathrm{V}_{\mathrm{cc}}$ power supply voltage. The Voltage doubler mode is enabled by setting the V2_EN bit (R[20]) to a HIGH level. The average delivery current of the doubler is less than the instantaneous current demand of the RF charge pump when active and is thus not capable of sustaining a continuous out of lock condition. A large external capacitor connected to $\mathrm{V}_{\mathrm{p}}(\approx 0.1 \mu \mathrm{~F})$ is therefore needed to control power supply droop when changing frequencies.

### 1.7 MICROWIRE ${ }^{\text {TM }}$ SERIAL INTERFACE

The programmable functions are accessed through the MICROWIRE serial interface. The interface is made of three functions: clock, data and latch enable (LE). Serial data for the various counters is clocked in from data on the rising edge of clock, into the 24 -bit shift register. Data is entered MSB first. The last two bits decode the internal register address. On the rising edge of LE, data stored in the shift register is loaded into one of the 4 appropriate latches (selected by address bits). A complete programming description is included in the following sections.

### 1.0 Functional Description (Continued)

### 1.8 FoLD Multifunction Output

The FoLD output pin can deliver several internal functions including analog/digital lock detects, and counter outputs. See programming description 2.4.2 for more details.

### 1.8.1 Lock Detect Output

A digital filtered lock detect function is included with each phase detector through an internal digital filter to produce a logic level output available on the $\mathrm{F}_{\mathrm{O}}$ LD output pin if selected. The lock detect output is high when the error between the phase detector inputs is less than 15 ns for 5 consecutive comparison cycles. The lock detect output is low when the error between the phase detector inputs is more than 30 ns for one comparison cycle. An analog lock detect status generated from the phase detector is also available on the $\mathrm{F}_{\mathrm{O}}$ LD output pin, if selected. The lock detect output goes high when the charge pump is inactive. It goes low when the charge pump is active during a comparison cycle. When a PLL is in power down mode, the respective lock detect output is always low. See programming descriptions 2.4.2.2-2.4.2.4.

### 1.9 OUTO/OUT1 Output Modes (FastLock \& CMOS Output Modes)

The OUT_0 and OUT_1 pins are normally used as general purpose CMOS outputs or as part of a FastLock scheme. There is also a production test mode that overrides the other two normal modes when activated. The selection of these modes is determined by the 4 bit CMOS register (F2_15-18) described in Table 2.5.3.
The FastLock mode allows the user to open up the loop bandwidth momentarily while acquiring lock by increasing the charge pump output current magnitude while simultaneously switching in a second resistor element to ground via the OUT0 output pin. The loop will lock faster without any additional stability considerations as the phase margin remains constant.
The loop bandwidth during FastLock can be opened up by as much as a factor of 4 . The amount of bandwidth increase is a function of the square root of the charge pump current increase. The maximum charge pump current ratio results from switching the charge pump current between $100 \mu \mathrm{~A}$ and 1.6 mA . The damping resistor ratio for these two charge pump current setting changes by the reciprocal of the bandwidth change. In the 4 to 1 bandwidth scenerio, the resulting damping resistor value would be $1 / 4$ th of the steady state value. This would be achieved by switching 3 more identical resistors in parallel with the first to ground through the OUT_0 pin.

### 1.10 POWER CONTROL

The PLL is power controlled by the device enable pin (CE) or MICROWIRE power down bit. The enable pin overrides the power down bit except for the V2_EN bit. When CE is high, the power down bit determines the state of power control. Activation of any PLL power down mode results in the disabling of the $N$ counter and de-biasing of $f_{I N}$ input (to a high impedance state). The $R$ counter functionality also becomes disabled when the power down bit is activated. The reference oscillator block powers down and the $\mathrm{OSC}_{\text {IN }}$ pin reverts to a high impedance state when CE or power down bit's are asserted, unless the V2_EN bit (R[20]) is high. Power down forces the charge pump and phase comparator logic to a TRISTATE condition. A power down counter reset function resets both $N$ and $R$ counters. Upon powering up the $N$ counter resumes counting in "close" alignment with the R counter (The maximum error is one prescaler cycle). The MICROWIRE control register remains active and capable of loading and latching in data during all of the power down modes.

### 2.0 Programming Description

### 2.1 MICROWIRE INTERFACE

The LMX2353 register set can be accessed through the MICROWIRE interface. A 24-bit shift register is used as a temporary register to indirectly program the on-chip registers. The shift register consists of a 24-bit DATA[21:0] field and a 2 -bit ADDRESS[1:0] field as shown below. The address field is used to decode the internal register address. Data is clocked into the shift register in the direction from MSB to LSB, when the CLK signal goes high. On the rising edge of Latch Enable (LE) signal, data stored in the shift register is loaded into the addressed latch.

| MSB | LSB |  |
| :--- | :--- | :--- |
|  | DATA [21:0] |  |

### 2.1.1 Registers' Address Map

When Latch Enable (LE) is transitioned high, data is transferred from the 24-bit shift register into the appropriate latch depending on the state of the ADDRESS[1:0] bits. A multiplexing circuit decodes these address bits and writes the data field to the corresponding internal register.


### 2.0 Programming Description (Continued)

### 2.2 R REGISTER

If the ADDRESS[1:0] field is set to 10 data is transferred from the 24 -bit shift register into the R register which sets the PLL's 15-bit R-counter divide ratio when Latch Enable (LE) signal goes high. The divide ratio is put into the R_CNTR[14:0] field and is described in section 2.2.1. The divider ratio must be $\geq 3$. The bits used to control the voltage doubler (V2_EN), Delay Lock Loop, (DLL_MODE), Charge Pump (CP_WORD) are detailed in section 2.2.2-2.2.4 below.

| Most Significant Bit |  |  |  |  |  |  |  |  | SHIFT REGISTER BIT LOCATION |  |  |  |  |  |  |  |  |  |  | Least Significant Bit |  |  |  |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| 23 | 22 | 21 | 20 | 19 | 18 | 17 | 16 | 15 | 14 | 13 | 12 | 11 | 10 | 9 | 8 | 7 | 6 | 5 | 4 | 3 | 2 | 1 | 0 |
| Data Field |  |  |  |  |  |  |  |  |  |  |  |  |  |  |  |  |  |  |  |  |  | Address Field |  |
| $\begin{aligned} & \hline \text { DLL } \\ & \text { MODE } \end{aligned}$ | $\begin{aligned} & \mathrm{V} 2 \\ & \mathrm{EN} \end{aligned}$ | CP_WORD[4:0] |  |  |  |  | R_CNTR[14:0] |  |  |  |  |  |  |  |  |  |  |  |  |  |  | 1 | 0 |
| $\begin{gathered} \mathrm{R} \\ 21 \end{gathered}$ | $\begin{aligned} & \mathrm{R} \\ & -20 \\ & \hline \end{aligned}$ | $\begin{gathered} \mathrm{R} \\ -19 \end{gathered}$ | $\begin{gathered} \mathrm{R} \\ -18 \\ \hline \end{gathered}$ | $\begin{gathered} \mathrm{R} \\ -17 \end{gathered}$ | $\begin{gathered} \mathrm{R} \\ -16 \end{gathered}$ | $\begin{gathered} \mathrm{R} \\ -15 \end{gathered}$ | $\begin{gathered} \mathrm{R} \\ -14 \\ \hline \end{gathered}$ | $\begin{gathered} \mathrm{R} \\ -13 \end{gathered}$ | $R$ 12 | $R$ <br> -11 | $\begin{gathered} \mathrm{R} \\ -10 \\ \hline \end{gathered}$ | R -9 | R | $R$ 7 | R -6 | $\begin{aligned} & \mathrm{R} \\ & \quad 5 \end{aligned}$ | $R$ -4 | R | $\begin{array}{r}R \\ 2 \\ \hline\end{array}$ | $R$ -1 | $R$ 0 |  |  |

### 2.2.1 Reference Divide Ratio (R_CNTR)

If the ADDRESS [1:0] field is set to 10 data is transferred MSB first from the 24-bit shift register into a latch which sets the 15 -bit R Counter, R_CNTR[14:0]. Serial data format is shown below.

|  | R_CNTR[14:0] |  |  |  |  |  |  |  |  |  |  |  |  |  |  |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| Divide Ratio | R_14 | R_13 | R_12 | R_11 | R_10 | R_9 | R_8 | R_7 | R_6 | R_5 | R_4 | R_3 | R_2 | R_1 | R_0 |
| 3 | 0 | 0 | 0 | 0 | 0 | 0 | 0 | 0 | 0 | 0 | 0 | 0 | 0 | 1 | 1 |
| 4 | 0 | 0 | 0 | 0 | 0 | 0 | 0 | 0 | 0 | 0 | 0 | 0 | 1 | 0 | 0 |
| - | - | - | - | - | - | - | - | - | - | - | - | - | - | - | - |
| 32,767 | 1 | 1 | 1 | 1 | 1 | 1 | 1 | 1 | 1 | 1 | 1 | 1 | 1 | 1 | 1 |

Note: R-counter divide ratio must be from 3 to 32,767 .

### 2.2.2 V2_EN (R_20)

The V2_EN bit when set high enables the voltage doubler for the charge pump supply.

| Bit | Location | Function | $\mathbf{0}$ | $\mathbf{1}$ |
| :---: | :---: | :---: | :---: | :---: |
| V2_EN | R_20 | Voltage Doubler Enable | Disable | Enabled |

2.2.3 DLL_MODE (R_21)

The DLL_MODE bit should be set to 1 for normal usage.

| Bit | Location | Function | $\mathbf{0}$ | $\mathbf{1}$ |
| :---: | :---: | :---: | :---: | :---: |
| DLL_MODE | R_21 | Delay Line Loop <br> Calibration Mode | Slow | Fast |

2.2.4 CP_WORD (R_15-R_19)

| R_19 | R_18 | R_17 | R_16 | R_15 |
| :---: | :---: | :---: | :---: | :---: |
| CP_8X | CP_4X | CP_2X | CP_1X | PD_POL |

### 2.2.4.1 Charge Pump Output Truth Table

| ICP $\mathbf{~} \boldsymbol{\mu A}$ (typ) | R_19 | R_18 | R_17 | R_16 |
| :---: | :---: | :---: | :---: | :---: |
|  | CP_8X | CP_4X | CP_2X | CP_1X |
| 100 | 0 | 0 | 0 | 0 |
| 200 | 0 | 0 | 0 | 1 |
| 300 | 0 | 0 | 1 | 0 |
| 400 | 0 | 0 | 1 | 1 |
| - | - | - | - | - |
| 900 | 1 | 0 | 0 | 0 |
| - | - | - | - | - |
| 1600 | 1 | 1 | 1 | 1 |

### 2.0 Programming Description (Continued)

### 2.2.4.2 Phase Detector Polarity (PD_POL)

Depending upon VCO characteristics, the PD_POL (R_15) bit should be set accordingly:
When VCO characteristics are positive like (1), PD_POL should be set HIGH;
When VCO characteristics are negative like (2), PD_POL should be set LOW.
VCO CHARACTERISTICS


### 2.3 N REGISTER

If the ADDRESS[1:0] field is set to 11 , data is transferred from the 24 -bit shift register into the N register which sets the PLL' s 19-bit N -counter, prescaler value, counter reset, and power-down bit. The 19 -bit N counter consists of a 4 -bit fractional numerator, FRAC_CNTR[3:0], a 5-bit swallow counter, A_CNTR[4:0], and a 10-bit programmable counter, B_CNTR[9:0]. Serial data format is show below. The divide ratio (NB_CNTR) must be $\geq 3$, and must be $\geq$ swallow counter +2 ; NB_CNTR $\geq$ (NA_CNTR +2).

| Mos | Signi | cant |  |  |  |  |  |  |  | IIFT | EG | TE | BI | L | CAT | ION |  |  |  |  | st |  |  |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| 23 | 22 | 21 | 20 | 19 | 18 | 17 | 16 | 15 | 14 | 13 | 12 | 11 | 10 | 9 | 8 | 7 | 6 | 5 | 4 | 3 | 2 | 1 | 0 |
|  |  |  |  |  |  |  |  |  | Data | Field |  |  |  |  |  |  |  |  |  |  |  | Addr | Field |
| CTL | VOR | :0] |  |  |  |  | _CN | R[9 |  |  |  |  |  | A_C | NTR | [4:0] |  |  | C_ | NTR |  |  |  |
| N | N | N | N | N | N | N | N | N | N | N | N | N | N | N | N | N | N | N | N | N | N | 1 | 1 |
| 21 | _20 | _19 | _18 | _17 | _16 | _15 | _14 | _13 | _12 | _11 | _10 | _9 | _ 8 | _7 | _6 | _5 | _4 | _3 | _2 | _1 | _0 |  |  |

### 2.3.1 CTL_WORD (N_19-N_21)

| N_21 | N_20 | N_19 |
| :---: | :---: | :---: |
| CNT_RST | PWDN | PRESC_SEL |

### 2.3.2 Control Word Truth Table

| Bit | Location | Function | $\mathbf{0}$ | $\mathbf{1}$ |
| :---: | :---: | :---: | :---: | :---: |
| PRESC_SEL | N_19 | Prescaler Modulus Select | $16 / 17$ <br> $(0.5 \mathrm{GHz}$ to 1.2 GHz$)$ | $32 / 33$ <br> $(1.2 \mathrm{GHz}$ to 2.5 GHz) |
| PWDN | N_20 | Power Down | Powered Up | Powered Down |
| CNT_RST | N_21 | Counter Reset | Normal <br> Operation | Reset |
| PWDN_MODE | F2_19 | Power Down Mode Select | Asynchronous <br> Power Down | Synchronous <br> Power Down |

### 2.3.2.1 Counter Reset (CNT_RST)

The Counter Reset enable bit when activated allows the reset of both N and R counters. Upon removal of the reset bit, the N counter resumes counting in "close" alignment with the R counter (the maximum error is one prescaler cycle).

### 2.3.2.2 Power Down (PWDN)

Activation of the PLL PWDN bit results in the disabling of the N counter divider and de-biasing of the $\mathrm{f}_{\mathrm{IN}}$ input (to a high impedance state). The R counter functionality also becomes disabled when the power down bit is activated. The $\mathrm{OSC}_{\text {IN }}$ pin reverts to a high impedance state as well during power down. Power down forces the charge pump and phase comparator logic to a TRI-STATE condition. The MICROWIRE control register remains active and capable of loading and latching in data during all of the power down modes.

### 2.3.2.3 Prescaler Modulus Select (PRESC_SEL)

The PRESC_SEL bit is used to set the RF prescaler modulus value. The LMX2353 is capable of operating from 500 MHz to 1.2 GHz with the $16 / 17$ prescaler, and 1.2 GHz to 2.5 GHz with the $32 / 33$ prescaler selection.

### 2.0 Programming Description (Continued)

### 2.3.2.4 Power Down Mode (PWDN_MODE)

## Synchronous Power Down Mode

The PLL loop can be synchronously powered down by setting the PWDN mode bit HIGH (F2_19=1) and then asserting the power down mode bit $(\mathrm{N} 20=1)$. The power down function is gated by the charge pump. Once the power down program bit is loaded, the part will go into power down mode upon the completion of a charge pump pulse event.

## Asynchronous Power Down Mode

The PLL loop can be asynchronously powered down by setting the PWDN mode bit LOW (F2_19=0) and then asserting the power down mode bit $(\mathrm{N} 20=1)$. The power down function is NOT gated by the charge pump. Once the power down program bit is loaded, the part will go into power down mode immediately.

### 2.3.3 Feedback Divide Ratio (NB Counter)

|  | NB_CNTR[9:0] |  |  |  |  |  |  |  |  |  |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| Divide Ratio | N_18 | N_17 | N_16 | N_15 | N_14 | N_13 | N_12 | N_11 | N_10 | N_9 |
| 3 | 0 | 0 | 0 | 0 | 0 | 0 | 0 | 0 | 1 | 1 |
| 4 | 0 | 0 | 0 | 0 | 0 | 0 | 0 | 1 | 0 | 0 |
| - | - | - | - | - | - | - | - | - | - | - |
| 1023 | 1 | 1 | 1 | 1 | 1 | 1 | 1 | 1 | 1 | 1 |

Note: B-counter divide ratio must be $\geq 3$.
NB_CNTR $\geq$ (NA_CNTR +2).

### 2.3.4 Swallow Counter Divide Ratio (NA Counter)

|  | NB_CNTR[4:0] |  |  |  |  |
| :---: | :---: | :---: | :---: | :---: | :---: |
| Divide Ratio | N_8 | N_7 | N_6 | N_5 | N_4 |
| 0 | 0 | 0 | 0 | 0 | 0 |
| 1 | 0 | 0 | 0 | 0 | 1 |
| $\cdot$ | $\bullet$ | $\cdot$ | $\bullet$ | $\bullet$ | $\cdot$ |
| 31 | 1 | 1 | 1 | 1 | 1 |

Note: Swallow Counter Value: 0 to 31.
NB_CNTR $\geq\left(N A \_C N T R+2\right)$.

### 2.3.5 Fractional Modulus Accumulator (FRAC_CNTR)

| Divide <br> Ratio | Divide <br> Ratio | FRAC_CNTR[3:0] |  |  |  |
| :---: | :---: | :---: | :---: | :---: | :---: |
| Modulus 15 | Modulus 16 | N_3 | N_2 | N_1 | N_0 |
| 0 | 0 | 0 | 0 | 0 | 0 |
| $1 / 15$ | $1 / 16$ | 0 | 0 | 0 | 1 |
| $2 / 15$ | $2 / 16$ | 0 | 0 | 1 | 0 |
| $\cdot$ | $\bullet$ | $\bullet$ | $\bullet$ | $\bullet$ | $\bullet$ |
| $14 / 15$ | $14 / 16$ | 1 | 1 | 1 | 1 |
| N/A | $15 / 16$ | 1 | 1 | 0 |  |

### 2.3.6 Pulse Swallow Function

$\mathrm{f}_{\mathrm{vco}}=[\mathrm{N}+\mathrm{F}] \times\left[\mathrm{f}_{\mathrm{osc}} / \mathrm{R}\right]$ where $\mathrm{N}=(\mathrm{PxB})+\mathrm{A}$
$\mathrm{f}_{\mathrm{Vco}}$ : Output frequency of external voltage controlled oscillator (VCO)
F: Fractional ratio (contents of FRAC_CNTR divided by the fractional modulus)
B: $\quad$ Preset divide ratio of binary 10 -bit programmable counter (3 to 1023)
A: Preset divide ratio of binary 5-bit swallow counter
$0<A<31\{P=32\} ;$
$0<A<15\{P=16\} ;$
$A+2<B$
$\mathrm{f}_{\text {Osc: }}$ : Output frequency of the external reference frequency oscillator

### 2.0 Programming Description (Continued)

R: Preset divide ratio of binary 15-bit programmable reference counter (3 to 32767)
$P$ : Preset modulus of dual modulus prescaler ( $\mathrm{P}=16$ or 32 )

### 2.4 F1 REGISTER

If the ADDRESS[1:0] field is set to 00 , data is transferred from the 24 -bit shift register into the F 1 register when Latch Enable (LE) signal goes high. The F1 register sets the fractional divider denominator FRAC_16 bit and $F_{\text {out }}$ Lock Dectect output $\mathrm{F}_{\mathrm{O}}$ LD word. The rest of the bits F1_0-F1_16, and F1_21 are Don't Care.

| Most Significant Bit |  |  |  |  |  |  |  |  | SHIFT REGISTER BIT LOCATION |  |  |  |  |  |  |  |  |  |  | Least Significant Bit |  |  |  |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| 23 | 22 | 21 | 20 | 19 | 18 | 17 | 16 | 15 | 14 | 13 | 12 | 11 | 10 | 9 | 8 | 7 | 6 | 5 | 4 | 3 | 2 | 1 | 0 |
| Data Field |  |  |  |  |  |  |  |  |  |  |  |  |  |  |  |  |  |  |  |  |  | Address Field |  |
| 0 | $\begin{gathered} \hline \text { FRAC } \\ \ldots 16 \end{gathered}$ | FoLD |  |  | These bits should be set to zero |  |  |  |  |  |  |  |  |  |  |  |  |  |  |  |  | 0 | 0 |
| $\begin{array}{r} \hline \text { F1 } \\ 21 \end{array}$ | $\begin{aligned} & \text { F1 } \\ & \quad 20 \end{aligned}$ | F1 -19 | F1 -18 | F1 -17 | F1 -16 | $\begin{gathered} \text { F1 } \\ \ldots 15 \end{gathered}$ | $\begin{gathered} \hline \text { F1 } \\ -14 \end{gathered}$ | F1 -13 | F1 <br> -12 | F1 -11 | F1 _10 | F1 | F1 | F1 | F1 | F1 | F1 | F1 | F1 | F1 | $\begin{aligned} & \mathrm{F} 1 \\ & \mathrm{C} \end{aligned}$ |  |  |

Note:0 denotes setting the bit to zero.

### 2.4.1 FRAC_16

The FRAC_16 bit is used to set the fractional compensation at either $1 / 16$ or $1 / 15$ resolution. When FRAC_16 bit is set to one, the fractional modulus is set to $1 / 16$ resolution, and FRAC_16 $=0$ corresponds to $1 / 15$. See section 2.3 .5 for fractional divider values.

| Bit | Location | Function | $\mathbf{0}$ | $\mathbf{1}$ |
| :---: | :---: | :---: | :---: | :---: |
| FRAC_16 | F1_20 | Fractional Modulus | $1 / 15$ | $1 / 16$ |

### 2.4.2 $\mathrm{F}_{\mathrm{O}} \mathrm{LD}$

The $\mathrm{F}_{\mathrm{o}}$ LD word is used to set the function of the Lock Detect output pin according to the Table 2.4.2.1 below. Open drain lock detect output is provided to indicate when the VCO frequency is in "lock". When the loop is locked and a lock detect mode is selected, the pin is HIGH, with narrow pulses LOW. See typical Lock detect timing in section 2.4.2.4.

### 2.4.2.1 $\mathrm{F}_{\mathrm{O}}$ LD Programming Truth Table

| F1_19 | F1_18 | F1_17 | FoLD Output State |
| :---: | :---: | :---: | :---: |
| 0 | 0 | 0 | Analog Lock Detect <br> (Open Drain) |
| 0 | 0 | 1 | Reserved |
| 0 | 1 | 0 | Digital Lock Detect |
| 0 | 1 | 1 | Reserved |
| 1 | 0 | 0 | Reserved |
| 1 | 0 | 1 | Reserved |
| 1 | 1 | 0 | N Divider Output |
| 1 | 1 | 1 | R Divider Output |

Reserved - Denotes a disallowed programming condition.

### 2.4.2.2 Lock Detect (LD) Digital Filter

The LD Digital Filter compares the difference between the phase of the inputs of the phase detector to a RC generated delay of approximately 15 ns . To enter the locked state (Lock $=\mathrm{HIGH}$ ) the phase error must be less than the 15 ns RC delay for 5 consecutive reference cycles. Once in lock (Lock = HIGH), the RC delay is changed to approximately 30 ns . To exit the locked state (Lock $=$ LOW), the phase error must become greater than the $30 \mathrm{~ns} \mathrm{RC} \mathrm{delay} .\mathrm{If} \mathrm{the} \mathrm{PLL} \mathrm{is} \mathrm{unlocked}$, will be forced LOW. A flow chart of the digital filter is shown next.

### 2.0 Programming Description (Continued)



### 2.4.2.3 Analog Lock Detect Filter

When the FoLD output is configured as analog lock detect output, an external lock detect circuit is needed in order to provide a steady LOW signal when the PLL is in the locked state. A typical circuit is shown below. It is noticed that $F_{0}$ LD is an "active low" open drain output.


### 2.0 Programming Description (Continued)

### 2.4.2.4 Typical Lock Detecting Timing



### 2.5 F2 REGISTER

If the ADDRESS[1:0] field is set to 0 1, data is transferred from the 24-bit shift register into the F2 register when Latch Enable (LE) signal goes high. The F2 register sets the CMOS output word bit CMOS[3:0] and the power down mode bit PWDN_MODE. The rest of the bits F2_0-F2_14, and F2_20-F_21 are Don't Care.

| Mos | Sign | an |  |  |  |  |  |  |  | IFT | G | TER | BI | LO | CAT |  |  |  |  |  | ast | igni | Bit |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| 23 | 22 | 21 | 20 | 19 | 18 | 17 | 16 | 15 | 14 | 13 | 12 | 11 | 10 | 9 | 8 | 7 | 6 | 5 | 4 | 3 | 2 | 1 | 0 |
| Data Field |  |  |  |  |  |  |  |  |  |  |  |  |  |  |  |  |  |  |  |  |  | Address Field |  |
| 0 | 0 | PWDN MODE | CMOS[3:0] |  |  |  | These bits should be set to zero |  |  |  |  |  |  |  |  |  |  |  |  |  |  | 0 | 0 |
| $\begin{aligned} & \text { F2 } \\ & 21 \\ & \hline \end{aligned}$ | $\begin{gathered} \text { F2 } \\ -20 \\ \hline \end{gathered}$ | $\begin{gathered} \text { F2 } \\ \quad 19 \end{gathered}$ | $\begin{gathered} \text { F2 } \\ -18 \end{gathered}$ | $\begin{gathered} \text { F2 } \\ -17 \end{gathered}$ | $\begin{gathered} \text { F2 } \\ \_16 \end{gathered}$ | $\begin{gathered} \text { F2 } \\ \_15 \end{gathered}$ | $\begin{gathered} \text { F2 } \\ \_14 \end{gathered}$ | $\begin{gathered} \text { F2 } \\ -13 \end{gathered}$ | $\begin{gathered} \text { F2 } \\ -12 \end{gathered}$ | F2 _11 | F2 | F2 | F2 | F2 | F2 | F2 | F2 | F2 | F2 | F2 | F2 |  |  |

Note:0 denotes setting the bit to zero

### 2.5.1 PWDN_MODE (F2_19)

See section 2.3.2 describing the control word and power down.

### 2.5.2 Programmable CMOS Outputs (F2_15-F2_18)

| F2_18 | F2_17 | F2_16 | F2_15 |
| :---: | :---: | :---: | :---: |
| FastLock | TEST | OUT_1 | OUT_0 |

### 2.5.3 OUTO/OUT1 Truth Table

| Bit | Location | Function | $\mathbf{0}$ | $\mathbf{1}$ |
| :---: | :---: | :---: | :---: | :---: |
| OUT_0 | F2_15 | Set the output logic level of <br> OUT0 pin | LOW | HIGH |
| OUT_1 | F2_16 | Set the output logic level of <br> OUT1 pin | LOW | HIGH |
| TEST | F2_17 | Test | Normal Operation | Test Mode |
| FastLock | F2_18 | FastLock Mode | CMOS Output Mode | FastLock Mode |

The CMOS[3:0] 4-bit register selects one of three modes for the OUT_0 and OUT_1 pins. The OUT_0 and OUT_1 pins are normally used as general purpose CMOS outputs or as part of a Fastlock ${ }^{\text {TM }}$ scheme. There is also a production test mode that overrides the other two normal modes when activated.
GENERAL PURPOSE CMOS OUTPUT MODE: The general purpose CMOS output mode is selected when the Fastlock ${ }^{\text {TM }}$ bit (F2_F18) and TEST bit (F2_17) are set LOW. The logic levels of the OUT_0 bit (F2_15) and OUT_1 bit (F2_16) then determine the logic states of the OUT_0 and OUT_1 pins.
Fastlock ${ }^{\top M}$ MODE: The Fastlock bit (F2_18) selects between the general purpose CMOS output or Fastlock ${ }^{\text {TM }}$ modes. The Fastlock ${ }^{T M}$ mode is selected when the Fastlock ${ }^{\text {TM }}$ bit is HIGH. The Fastlock ${ }^{\text {TM }}$ mode allows the user to open up the loop bandwidth momentarily while acquiring lock by increasing the charge pump output current magnitude while simultaneously switching in a second resistor element to ground via the OUTO output pin.

### 2.0 Programming Description (Continued)

The low gain or steadystate mode for fastlocking is defined to be whenever the charge pump current selected is less than 900 $\mu \mathrm{A}$. The high gain or acquisition mode is defined to be whenever the charge pump current is greater or equal to $900 \mu \mathrm{~A}$. (The logic setting of the CP_8X bit determines which of the two gain modes the user is in.) During the acquisition phase when the CP_8X bit is set to a HIGH state, the OUTO output becomes active LOW thereby altering the loop's damping resistance.
The acquisition phase is terminated by setting the CP_8X bit LOW resulting in the OUT0 output being OFF or TRI-STATE. When in fastlock mode, the OUT_0 and OUT_1 bits are don't care bits, and the OUT1 output is at TRI-STATE.
TEST MODE: The OUT0/OUT1 test mode occurs when the TEST bit (F2_17) is set HIGH. This mode is intended for NSC production test only. Selecting this mode overrides the Fastlock ${ }^{\text {TM }}$ and GEN PURPOSE modes.

### 2.5.4 Serial Data Input Timing



Notes: Data shifted into register on clock rising edge.
Data is shifted in MSB first.
Test Conditions: The Serial Data Input Timing is tested using a symmetrical waveform around $\mathrm{V}_{\mathrm{cc}} / 2$. The test waveform has an edge rate of $0.6 \mathrm{~V} / \mathrm{ns}$ with amplitudes of $2.2 \mathrm{~V} @ \mathrm{~V}_{\mathrm{CC}}=2.7 \mathrm{~V}$ and $2.6 \mathrm{~V} \mathrm{~V}_{\mathrm{CC}}=5.5 \mathrm{~V}$.

Physical Dimensions inches (millimeters) unless otherwise noted


Physical Dimensions inches (millimeters) unless otherwise noted (Continued)


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